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# Characteristics of SnO<sub>2</sub> annealed in reducing atmosphere

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#### Abstract

The characteristics of  $SnO_2$  reduced in  $H_2/N_2$  at various annealing temperatures are reported. The formation of polycrystalline metallic Sn from  $SnO_2$  is detected by X-ray diffraction above the annealing temperature of  $500\,^{\circ}C$ . The photoluminescence (PL) characteristics of reduced  $SnO_2$  have been studied as a function of temperature. Further studies of Fourier transform infrared (FTIR), differential thermal analysis (DTA- $T_g$ ), and photoluminescence excitation (PLE) spectroscopy have been performed. Broad emission with peaks at around  $590\,\text{nm}$  (2.1 eV) and  $420\,\text{nm}$  is obtained from  $SnO_2$ . The reduced  $SnO_2$  shows an increase PL intensity of  $420\,\text{nm}$  band. In addition the PL intensity of reduced  $SnO_2$  at  $420\,\text{nm}$  (2.95 eV) increases with annealing in ambient air. The origin of luminescence bands detected in reduced tin oxide is discussed.

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### 1. Introduction

Tin oxide (SnO<sub>2</sub>), an n-type semiconductor with a wide band gap ( $E_{\rm g}=3.6~{\rm eV}$ , at 300 K), is extensively used as a functional material for the optoelectronic devices [1], conductive electrodes and transparent coatings due to its good conductivity and transparency in the visible spectrum [2,3], solar cells [4,5], and catalyst support [6]. The variation of grain size, the concentration of oxygen vacancies and electrical properties of tin oxide as bulk as well as thin films are also widely studied. Along with these applications, tin oxide is an attractive material in developing solid-state sensors for reducing gases such as CO, NO, and  $C_2H_5OH$  [7–9].

Considerable efforts have been put forth to develop metal oxide semiconductor materials (SnO<sub>2</sub>), especially the preparation of thin film and properties, which may lead to novel optoelectronic devices. The reported luminescence bands from SnO<sub>2</sub> are at around 2.4–2.5 eV and 2.9–3.1 eV [10–12]. The origins of these luminescence bands are not

clearly understood. In general, oxygen vacancies, which usually act as radiative centers, play an important role in the luminescence properties of the metal oxide semiconductors. However, no reports exist on the luminescence properties of reduced  $SnO_2$ . Therefore, it is of interest to study the characteristics of  $SnO_2$  in reducing atmosphere and its luminescence properties.

The characteristics of SnO<sub>2</sub> prepared in reducing atmosphere are analyzed through PL and PLE, XRD, FTIR, and DTA and the possible mechanism of luminescence bands are discussed.

### 2. Experimental

 $SnO_2$  powders (Aldrich Chemical Co., 99.99% purity) were pressed into cylindrical pellets (1 mm thick and 5 mm in diameter) at 1000 psi, sintered at 1350 °C for 1 h under ambient air, and placed into an high purity alumina boat and reduced in  $H_2N_2$  (5%  $H_2$ ) atmosphere with a flow of 20 sccm for the duration of 1 h at various temperatures (400–630 °C). The reduction temperature above 650 °C yielded wetting and melting of  $SnO_2$ .

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The XRD patterns of the samples were examined using a Rigaku X-ray diffractometer with monochromatized Cu  $K\alpha$  radiation.

The PL equipment consists of a He–Cd laser, 50-mm collection optics, a 0.5-m scanning grating monochromator and an air-cooled GaAs photomultiplier. A long-pass filter was inserted after the sample to block any scattered laser light. The temperature dependence of PL was measured by placing the sample in the cold finger of a closed-cycle He refrigerator that allows settings between 20 K and 300 K.

For PLE measurements, a 1000 W Xe lamp was used to generate white light, which passed through a  $0.15\,\mathrm{m}$  single grating scanning monochromator into a sample chamber. The 2 mm  $\times$  3 mm beam size of scanning light was detected by a Si detector before illuminating the sample and then the excitation spectrum was dispersed by a 0.5-m single grating monochromator. The spectrum was collected by an aircooled GaAs photomultiplier.

The Fourier transform infrared spectra of samples were observed by diffuse reflection spectroscopy in a vacuum chamber.

## 3. Results and discussion

X-ray diffraction (XRD) measurements of sintered  $SnO_2$  and reduced  $SnO_2$  are depicted in Fig. 1. The diffraction peaks of sintered  $SnO_2$  display a good compatibility with JCPDS 41-1445. No characteristic peaks of impurities were observed from  $SnO_2$  sintered in air. The calculated lattice constants and unit cell volume of sintered tetragonal  $SnO_2$  are a = 4.733 Å, b = 3.184 Å, and 71.33 Å<sup>3</sup>, respectively, and agree to the values obtained from the JCPDS. The diffraction

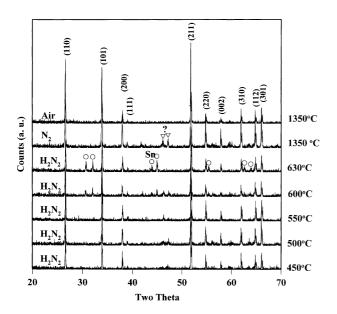


Fig. 1. XRD patterns of  $SnO_2$  and reduced  $SnO_2$  at various temperatures. The diffraction peaks originating from Sn are depicted as open circles.

peaks of SnO<sub>2</sub> reduced in N<sub>2</sub> ambience exhibit the characteristics of SnO<sub>2</sub> with somewhat increased diffraction peak intensities and almost identical values of lattice constants and unit cell volume of SnO<sub>2</sub> obtained from the JCPDS. There exists two unidentified diffraction peaks at the 46.17° and 47.12°. However, the intensities of this unknown diffraction peak decrease in H<sub>2</sub>N<sub>2</sub> ambient annealing with an increase of annealing temperature. The SnO<sub>2</sub> reduction by H<sub>2</sub>N<sub>2</sub> annealing displays a general trend of lattice constants and unit cell volume to decrease. XRD diffraction patterns of reduced SnO<sub>2</sub> specimens in H<sub>2</sub>N<sub>2</sub> also display diffraction peaks originating from polycrystalline Sn depicted as an open circle. It is generally observed that the ambient annealing of SnO2 resulted in a gray body color above 500 °C. H<sub>2</sub>N<sub>2</sub> annealing above 630 °C resulted in melting of the specimen. For Sn, a small contraction of lattice constants (a = 5.826 Å, b = 3.178 Å) compared to JCPDS 04-0673 (a =5.831 Å, b = 3.182 Å) were observed, and resulted in a decrease of the unit cell volume (107.82 Å<sup>3</sup>). It seems the decrease in lattice constants and unit cell volume of SnO<sub>2</sub> to be associated with the thermal stress and the increase of oxygen vacancies during the reduction process.

The weight loss as a function of annealing temperature is shown in Fig. 2. Initial weight loss of  $SnO_2$  in air is relatively high up to 400 °C and then its rate decreases above 400 °C. In contrast the weight loss of  $SnO_2$  in  $H_2N_2$  atmosphere shows a rapid decrease above 500 °C, which is related to rapid oxygen desorption. This result agrees quite well with the XRD analysis. XRD analysis of reduced  $SnO_2$  in  $H_2N_2$  displays diffraction peaks originating from polycrystalline Sn above 500 °C as shown in Fig. 1.

Fig. 3 displays PL spectra of  $SnO_2$  prepared in air (e) in  $N_2$  atmosphere (f), and reducing  $H_2N_2$  (a–d) atmosphere measured at room temperature. All of the measured  $SnO_2$  PL

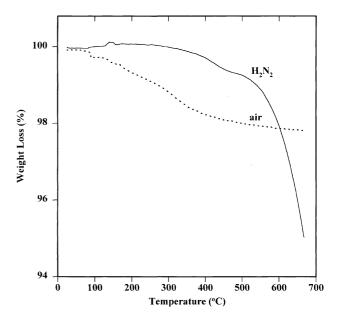


Fig. 2. The weight loss curves of  $SnO_2$  as a function of temperatures in air and reduced  $H_2N_2$  atmosphere.

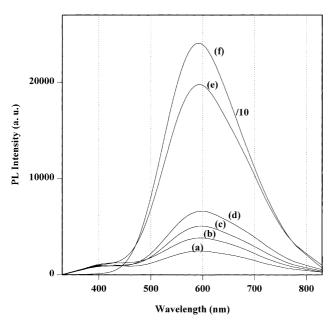


Fig. 3. Room temperature photoluminescence spectra of (a–d) sintered in  $N_2$ , and subsequently reduced  $H_2N_2$  atmosphere. The reduced temperatures of (a–d) are 450, 550, 600, and 630 °C, respectively. The PL spectra of (e) sintered  $SnO_2$  in air and (f)  $N_2$  atmosphere at 1350 °C for 2 h.

spectra are quite similar to shape and positions of PL peaks. Luminescence bands peaking at 420 nm and 590 nm have been detected. The PL intensity of  $SnO_2$  prepared in  $N_2$  atmosphere is one order of magnitude larger than for  $SnO_2$  prepared in air. Thus, the reduction of  $SnO_2$  in  $H_2N_2$  utilized the samples prepared in  $N_2$  atmosphere for this study. The utilization of sintered  $SnO_2$  in ambient air does not change the result of annealing in reducing atmosphere. The intensity of 590 nm luminescence band tends to decrease with the reduction temperature from 450 °C to 630 °C (curve (a–d)). In contrast the PL intensity of 420 nm luminescence band is slightly reduced throughout  $H_2N_2$  reduction.

Fig. 4 depicts the room temperature PL spectra of  $SnO_2$  reduced at 630 °C with various annealing intervals (up to 31 days). The PL spectra were measured within 20 min after reduction in  $H_2N_2$  atmosphere. The most noticeable change of PL spectra of  $SnO_2$  is that the weak shoulder luminescence in the blue/violet spectral region of reduced  $SnO_2$  now becomes a very pronounced peak with ambient air annealing. After 1 month of ambient air annealing of  $SnO_2$  reduced in  $H_2N_2$ , the intensity of 420 nm and 590 nm luminescence bands are quite comparable to each other. This increase of the blue/violet luminescence band might be related to the oxidation in air atmosphere after reduction.

Fig. 5 depicts the decrease of PL intensity as a function of UV laser exposure at a power density of 1 W/cm $^2$ . For this measurements 1-month ambient air aged SnO $_2$  reduced in H $_2$ N $_2$  atmosphere is used. The decrease of PL intensity as a function of UV exposure is measured at the maxima of PL peak, namely 420 nm and 590 nm. Both luminescence bands display PL stability under UV exposure. The blue/violet

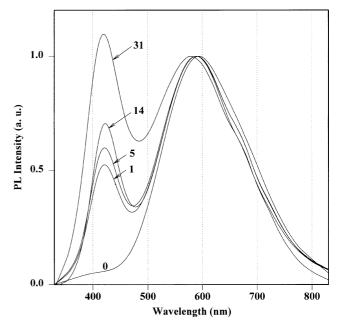


Fig. 4. Room temperature PL spectra of  $SnO_2$  reduced in  $H_2N_2$  at 630  $^{\circ}C$  as a function of annealing time intervals (day).

luminescence band is a little bit more sensitive to the UV exposure.

Fig. 6 shows various PL spectra measured at selected temperatures to delineate possible similarities and differences between (a)  $SnO_2$  prepared in  $N_2$  at 1350 °C and (b) sintered, reduced in  $H_2N_2$ , and subsequently annealed in air for 1 month. The sintered  $SnO_2$  exhibits a broad yellow

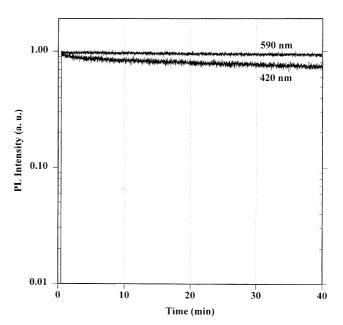
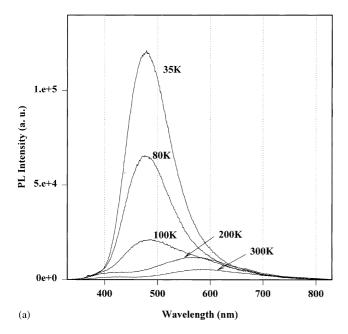


Fig. 5. The decrease of PL intensity as a function of UV laser exposure time at a power density of  $1~\text{W/cm}^2$ . The 1-month ambience air aged  $\text{SnO}_2$ , which is reduced in  $\text{H}_2\text{N}_2$  ambience, are used. The wavelengths are selected at luminescence peak maxima at 420 nm and 590 nm.



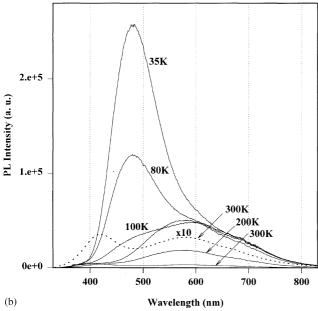


Fig. 6. PL spectra of (a) SnO<sub>2</sub> prepared in N<sub>2</sub> at 1350 °C and (b) reduced, and subsequently ambient air annealed for 1 month at some selected temperatures. Measurement temperatures are indicated.

luminescence band around 590 nm (2.1 eV) with a shoulder blue/violet luminescence band around 420 nm (2.95 eV). The sintered, reduced, and subsequently ambient annealed  $\rm SnO_2$  also shows a similar blue/violet and yellow luminescence band with similar PL intensities at room temperature. Initially, the yellow luminescence of both samples is shifted to 480 nm at 35 K. Further, the blue/violet luminescence at around 420 nm remains unaltered and displays the same trend as a function of temperature. Therefore, the yellow luminescence and blue/violet luminescence from sintered  $\rm SnO_2$  and reduced  $\rm SnO_2$  are associated with same origins. The semiconducting behavior

of tin oxide is attributed to the presence of oxygen vacancies in the bulk lattice, which act as shallow n-type donors. The structural and electronic properties of tin oxide that stem from oxygen vacancies are critical to the electrical and optical properties [13]. It has been reported that the bridging and in-plane oxygen vacancies are characterized by occupied states higher in the band gap, which extends to the Fermi level [14]. These trapped states originating from oxygen vacancies form a series of metastable energy levels within the band gap. Thus, the observed origin of orange luminescence is probably related to a defect energy band within the band gap of SnO<sub>2</sub> originating from oxygen vacancies. A similar broad luminescence band at 2.4 eV is also observed from SnO<sub>2</sub> thin films grown by chemical vapor deposition and the origin of luminescence is assigned to oxygen vacancies [12].

It is quite interesting that the blue/violet luminescence between sintered SnO<sub>2</sub> and reduced SnO<sub>2</sub> displays a similar trend (unaltered peak positions) as a function of temperature. The blue/violet luminescence bands at 400 nm and 430 nm from SnO<sub>2</sub> are also reported by several researchers [10–12]. The origin of blue/violet luminescence form SnO<sub>2</sub> is attributed to oxygen vacancies, tin interstitial or dangling bond, and structural defects. XRD shows that the SnO2 reduced in H<sub>2</sub>N<sub>2</sub> displays polycrystalline Sn with increase of reducing temperature. Further, ambient annealing of reduced SnO<sub>2</sub> demonstrates the increase of blue/violet luminescence band. Thus, the origin of the blue/violet luminescence band seems to be related to Sn interstitials and nonstoichiometric oxide. As reduction temperature increase, the amount of Sn and nonstoichiometry increases with the decrease of oxygen vacancies, which result in an increase of blue/violet luminescence band with a decrease of the broad yellow luminescence. Further, ambient air annealing of reduced SnO<sub>2</sub> gradually increases the oxidation of Sn and passivates the surface with oxygen nonstoichiometrically, and results in an overall increase of blue/violet luminescence.

Fig. 7 shows typical photoluminescence excitation (PLE) spectra for sintered SnO<sub>2</sub> and reduced SnO<sub>2</sub> measured at the luminescence peak maxima. Curves (a and b) depict the PLE spectra of sintered SnO<sub>2</sub>, and reduced SnO<sub>2</sub>, respectively. The PL spectra measured at room temperature and low temperature display quite similar results, as shown in Figs. 3 and 6. Thus, it is expected that the same PLE spectra should be obtained from sintered SnO<sub>2</sub> and reduced SnO<sub>2</sub>. Indeed similar shapes of PLE spectra are obtained for both samples. The reduced SnO<sub>2</sub> displays only the decreased the intensity of PLE spectra. A large number of absorption peaks are identified, which are measured at 420 nm. In the UV region, a strong absorption band at near 3.29 (377 nm) is detected along with a weak absorption peak at 4.66 eV (266 nm) and 3.9 eV (317 nm). The band gap of SnO<sub>2</sub> is 3.6 eV. Thus, any electrons pumped into excited states by a 3.82 eV (325 nm) He-Cd laser from ground state resulted in de-excitation into a 3.29 eV (377 nm) absorption band, then they revert to

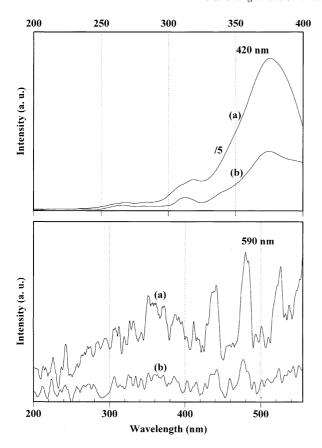


Fig. 7. PLE spectra of (a)  $SnO_2$  prepared in  $N_2$  at 1350 °C and (b) reduced, and subsequently ambient air annealed for 1 month. The wavelengths are selected at luminescence peak maxima at 420 nm and 590 nm.

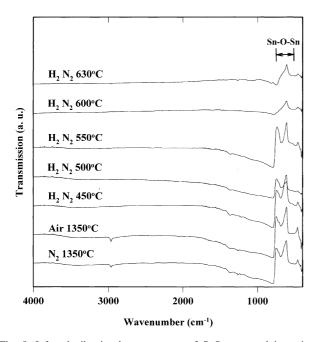


Fig. 8. Infrared vibrational spectroscopy of  $SnO_2$  prepared in various conditions.

2.95 eV (420 nm) via nonradiative transition, and finally return to ground state via radiative transitions. When the PLE spectra are obtained at 590 nm (2.1 eV) for sintered  $\text{SnO}_2$  one could detect a broad absorption band from 250 nm to 400 nm and three narrow absorption bands at around 440 nm (2.82 eV), 479 nm (2.59 eV), and 525 nm (2.36 eV). At present it is difficult to assign these three narrow absorption bands, but they seem to relate to different types of oxygen vacancies and crucial to the emission of 2.1 eV. Further work is necessary to identify this.

The PL spectra of sintered  $SnO_2$  exhibited almost identical luminescence peaks to the reduced  $SnO_2$  in  $H_2N_2$  ambience. Further PLE spectra of  $SnO_2$  and reduced  $SnO_2$  show significant similarities with respect to absorption bands. Thus, it is expected that the vibrational mode of  $SnO_2$  and reduced  $SnO_2$  would be quite similar. To test this, infrared vibrational spectra have been measured for  $SnO_2$  and reduced  $SnO_2$  and the results are shown in Fig. 8. The infrared spectra of  $SnO_2$  and reduced  $SnO_2$  are dominated by the vibration around  $600 \text{ cm}^{-1}$ , which is associated with an asymmetric Sn-O-Sn stretching vibrational mode [15]. It is noted that vibrational modes of  $SnO_2$  and reduced  $SnO_2$  are quite similar as can be seen in the figure.

### 4. Conclusions

Polycrystalline Sn has been detected to form above  $500\,^{\circ}\text{C}$  from  $\text{SnO}_2$  reduced in  $\text{H}_2\text{N}_2$ , as demonstrated by XRD. The sintered  $\text{SnO}_2$  and reduced  $\text{SnO}_2$  in  $\text{H}_2\text{N}_2$  atmosphere yield a luminescence band around 420 nm and 590 nm. The experimental results of low temperature PL and PLE measurements reveal that the origin of the luminescence band observed form  $\text{SnO}_2$  and reduced  $\text{SnO}_2$  is the same for each luminescence band. The blue/violet luminescence bands at 420 nm and yellow luminescence band at 590 nm are due to the Sn interstitial and nonstoichiometry and oxygen vacancies, respectively.

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